

**Search Notes**

Application/Control No.

10/725,451

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

KAKUO ET AL.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner
424	725	8/4/2006	PL
424	758	8/4/2006	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
424	758	8/2/2006	PL
424	725	8/2/2006	PL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE	7/29/2006	PL
updated STN: Indexed BIOSCIENCE cluster (76 databases)	7/31/2006	PL
Updated inventor name search PALM/EAST	8/4/2006	PL